


<b>Search Notes</b>  	<b>Application/Control No.</b>  10590791	<b>Applicant(s)/Patent Under Reexamination</b>  HEUER ET AL.
	<b>Examiner</b>  Quoc A Tran	<b>Art Unit</b>  2176

SEARCHED			
Class	Subclass	Date	Examiner
715	234	8/28/2008	QT
715	235-250	8/28/2008	QT
Updated	Updated	2/10/2009	QT
Updated	Updated	5/21/2009	QT
Updated	Updated	11/4/2009	QT
Updated	Updated	6/15/2010	QT

SEARCH NOTES		
Search Notes	Date	Examiner
NPL Search (ACM; Google Scholar; Scirus Digital Library)	8/28/2008	QT
EAST (USPAT, USPGPUB, JPO, USOCR, FPRS, EPO, DERWENT & IBM_TDB)	8/28/2008	QT
Inventors Searched Conducted- Considered Double Patent Rejection	8/28/2008	QT
Text Search Class 715/234-250	8/28/2008	QT
Updated	2/10/2009	QT
Updated	5/21/2009	QT
Updated	11/4/2009	QT
Updated	6/15/2010	QT

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
715	260	6/15/2010	QT
709	219 and 227	6/15/2010	QT
726	5	6/15/2010	QT

/Quoc A Tran/ Examiner.Art Unit 2176	
---	--